LDEOC/EOEC SURVEILLANCE PANEL

A LDEOC/EOEC conference call was held on 6-30-20 at 9 am Central Standard Time. The following esteemed members were on the call:

Mike Lopez - Intertek
Kimberly Hernandez - Intertek
Mike Birke – SwRI
Jason Bowden – OHT
Doyle Boese – Infineum
Conika Own-Robinson – Savant
Vince Donndelinger - Lubrizol
Robert Stockwell – Oronite
Laura Birnbaumer - Oronite
Gefei Wu - Valvoline
Becky Grinfield – SwRI
Kai Malyska - ISP
Tom Schofield - TMC
Joe Franklin - Intertek

The purpose of the call was to discuss/approve the LDEOC batch 24 ACM-1 Volume Change Industry Correction Factor. Doyle presented the statistical data (attached). Based on the statistical analysis, the recommendation is to apply an industry correction factor of -2.43%. There was no discussion. Jason Bowden made a motion to accept -2.43% as the Volume Change Industry Correction Factor for LDEOC Batch 24 ACM-1. The motion was unanimously approved and the motion carried. Laura Birnbaumer had a question on the status of the pass/fail EOEC limits. Joe Franklin informed her that is class panel business, and not that of the surveillance panel. Tom Schofield brought up new business. He intends to make corrections to the report forms and data dictionary for both LDEOC and EOEC. Silicone has been spelled incorrectly as “silicon”. He made a motion to approve the corrections, which was met with another unanimous approval.

There was no other business and the call adjourned at 9:17 am.

LDEOC ACM-1 Batch 24 Industry Correction Factor

D. Boese

June 23, 2020

Performance you can rely on.

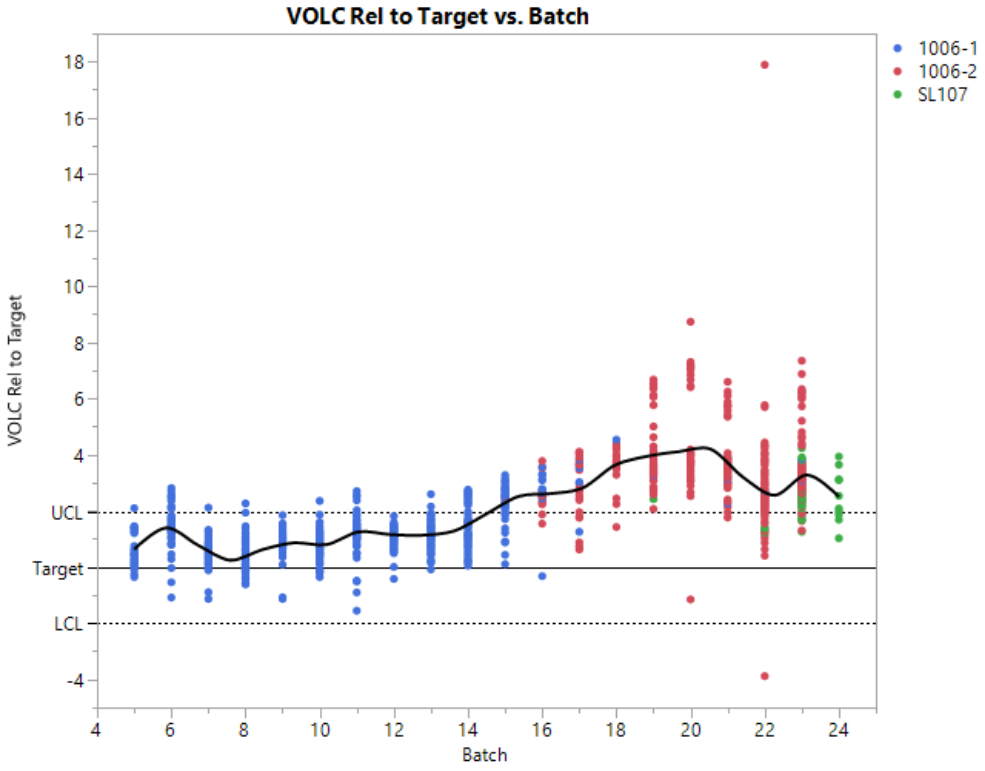
Summary

- Recommend a Volume Change Industry Correction Factor (ICF) of -2.43% for Batch 24 ACM-1.
- Batch 24 ACM-1 sample averages for HARD and TENS are within 1.5 and 1 standard deviation of target, respectively.

Data

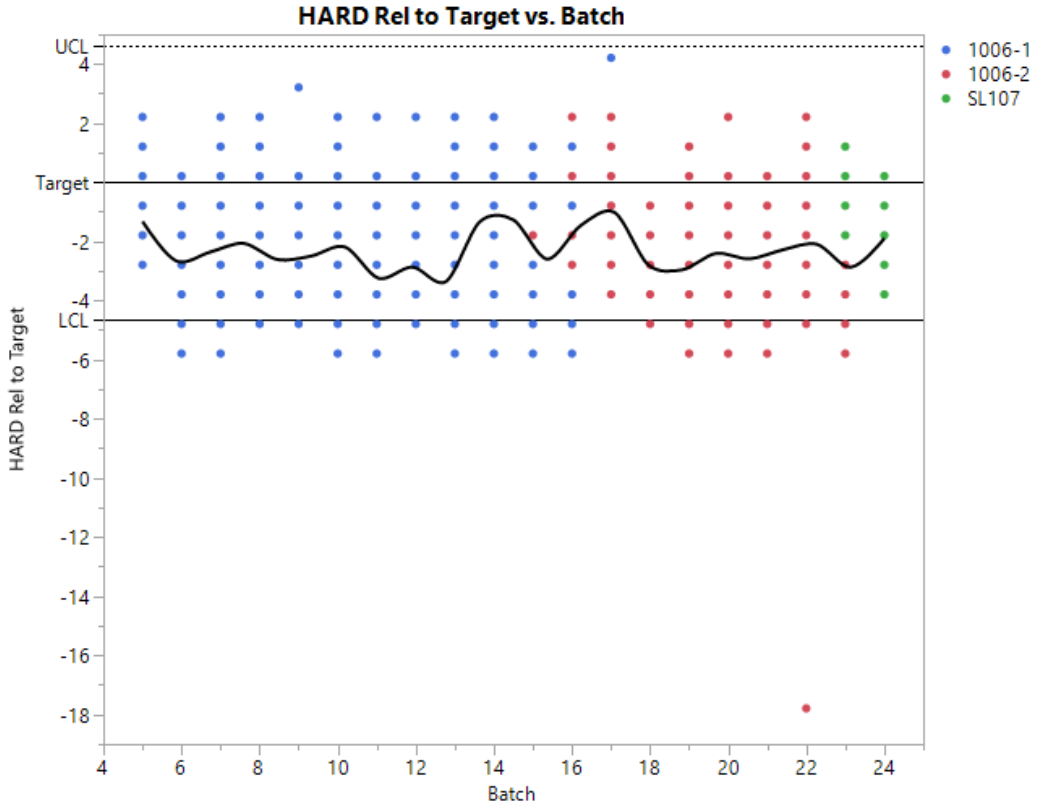
- The data is as of June 20, 2020.
- Five labs (A, B, E, G, and I) each ran in separate baths 2 tests of Batch 24 ACM-1.
  - Four labs (A, B, G and I) included in each bath a Batch 23 ACM-1 as a reference. The results of these tests are included in the ICF estimation calculation.
  - Data from lab E is included with the other 4 labs in each of the plots.

Unadjusted Volume Change Relative to Target



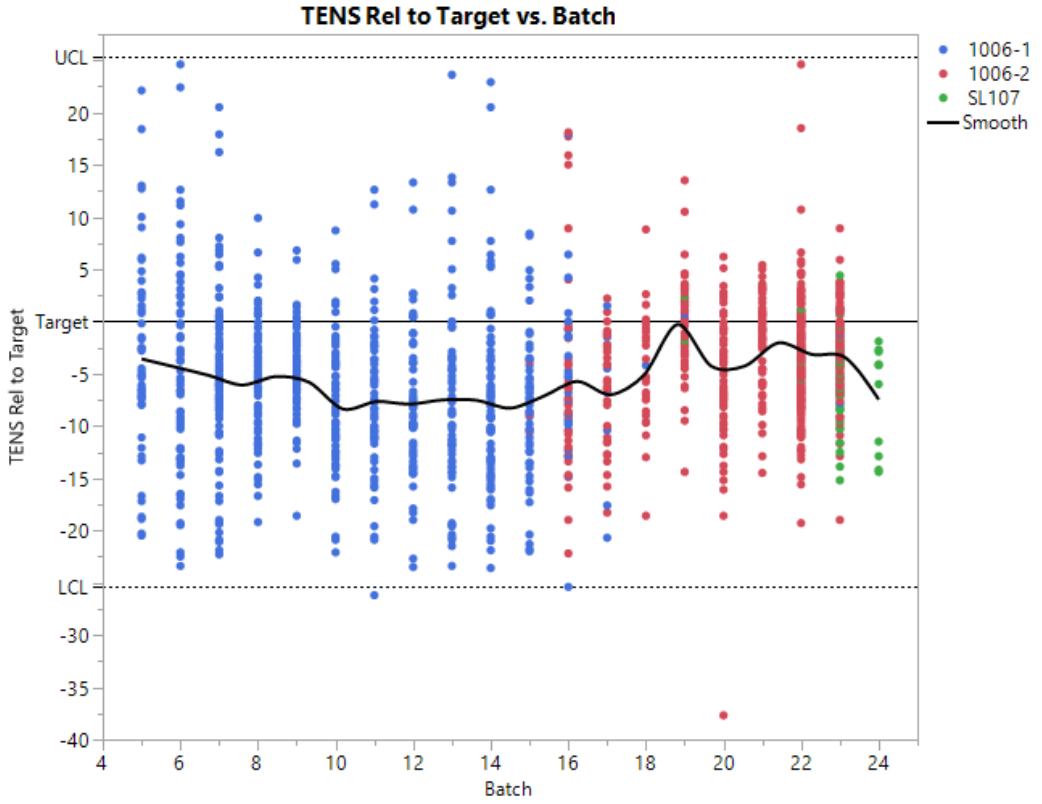
- Plotted is Volume Change without ICF relative to the applicable target for batches at the current targets for RO 1006 and SL107.
  - Only operationally valid data are plotted.
- Batch 24 VOLC appears slightly lower than Batch 23
- 7 of the 10 unadjusted Batch 24 VOLC results are higher than the upper calibration limits.

Hardness Change



- Plotted is HARD Relative to Target for batches at the current targets for RO 1006 and SL107.
  - Only operationally valid data are plotted.
- Batch 24 HARD appears similar to previous batches.
- All 10 unadjusted Batch 24 HARD results are within the calibration limits but all but 1 are below target.

Tensile Strength Change



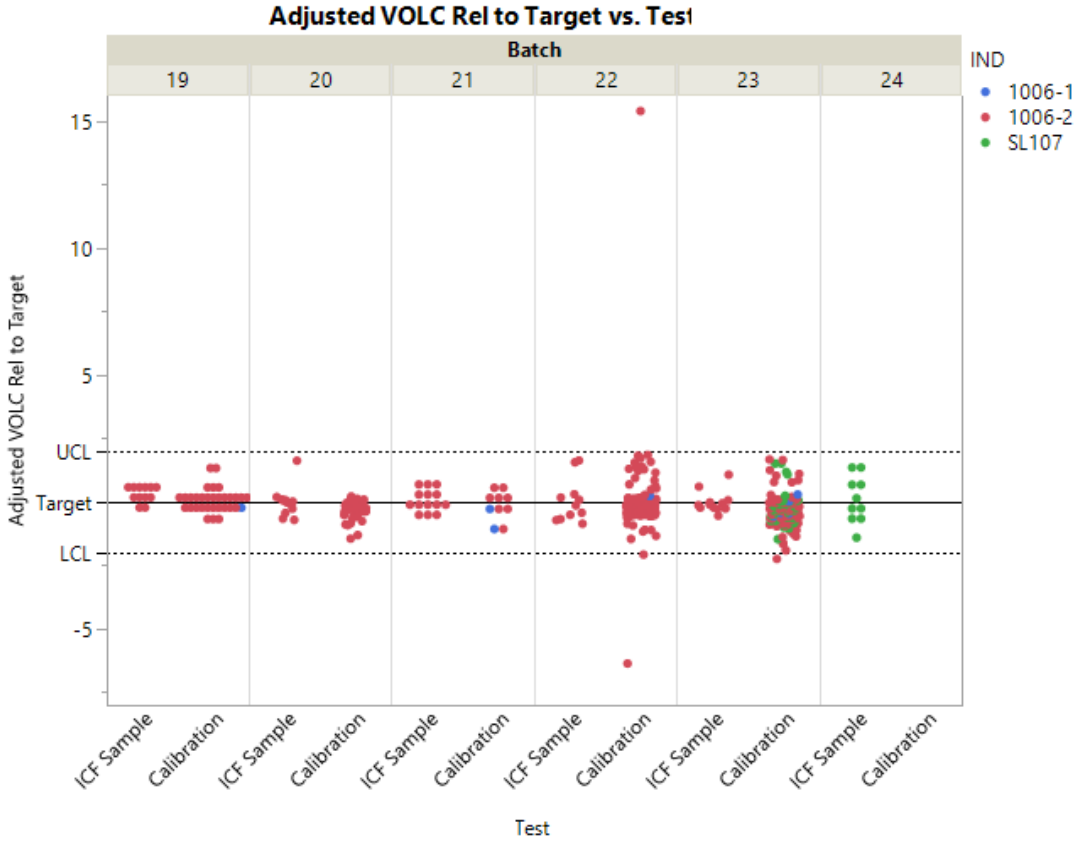
- Plotted is TENS Relative to Target for batches at the current targets for RO 1006 and SL107.
  - Only operationally valid data are plotted.
- Batch 24 TENS appears lower relative to recent batches.
- All 10 unadjusted Batch 24 TENS results are within the calibration limits but all are below target.

Industry Correction Factor

- The ICF (Target – Batch 24 Average + Severity Adjustment) for VOLC is -2.43% and is statistically significant.
- ICFs are not calculated for HARD and TENS.

Statistic	VOLC	HARD	TENS
Target	2.05	-0.21	2.58
Batch 23 Cal Avg	2.24	-1.88	0.26
Batch 24 Avg	4.67	-2.00	-5.89
Batch 23 Delta	0.19		
Batch 24 Avg Sev Adj	4.48		
Batch 24 Delta	2.43		
Batch 24 ICF	-2.43		
p-Value	< 0.0001		

Volume Change with ICF Applied



Batch	IFC
19	-2.65
20	-3.14
21	-2.53
22	-1.65
23	-2.72
24	-2.43

- ICFs were applied to each Batch including the proposed ICF for Batch 24.
- ICFs are adjusting VOLC within Calibration Limits.
- Calibration VOLC results generally being within Calibration Limits indicates the sample size of the ICF Calculation Sample is sufficient.

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